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Search Notes

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Examiner

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JI ET AL.

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SEARCHED

Class	Subclass	Date	Examiner
252	79.1	8/2/2006	BT
252	79.3	8/2/2006	BT

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	8/2/2006	BT